

# **Notice of References Cited**

Application/Control No.

10/031,036

Applicant(s)/Patent Under  
Reexamination  
BRYDEN ET AL.

Examiner

Jon P Weber, Ph.D.

Art Unit

1651

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	White et al., "Rapid Identification of Microbes from Clinical and Environmental Matrices", in "Mass Spectrometry for the Characterization of Microorganisms (Symposium Series)", (1994) Fenselau, C. (Ed.), Vol. 541, American Chemical Society, Washington DC, <i>pages 8 and 14</i>			
	V	Emokhonov et al., "Detection of Grain Infection with Specific Toxicogenous Fungal Species" in "Mass Spectrometry for the Characterization of Microorganisms (Symposium Series)", (1994) Fenselau, C. (Ed.), Vol. 541, American Chemical Society, Washington DC, <i>pages 85-90</i>			
	W	Lauritsen et al., "Direct Detection of Volatile Metabolites Produced by Microorganisms" in "Mass Spectrometry for the Characterization of Microorganisms (Symposium Series)", (1994) Fenselau, C. (Ed.), Vol. 541, American Chemical Society, Washington DC, <i>91 and 97-98</i>			
	X	Roboz, J., "Mass Spectrometric Determination of D- and L-Arabitol Ratios for Diagnosis and Monitoring of Disseminated Candidiasis" in "Mass Spectrometry for the Characterization of Microorganisms (Symposium Series)", (1994) Fenselau, C. (Ed.), Vol. 541, American Chemical Society, Washington DC, <i>pages 132-146</i>			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.